## Application/Control No. Applicant(s)/Patent Under Reexamination 10/826,589 SEIDL ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Hiep T. Nguyen 2187 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,950,838 09-2005 Wright et al. 707/206 Α US-6,470,361 10-2002 Alpern et al. 707/206 В С US-US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY N 0 P Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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